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Application Number

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Concurrently Herewith 319/2404

First Named Inventor

Young-pil Kim et al.

Group Art Unit

UNKNOWN 2015

Examiner Name

UNKNOWN 2813
UNKNOWN 100101

Attorney Docket Number

5649-1276

[illegible][illegible]

OTHER NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-Issue number(s), publisher, city and/or country where published	T
<i>ML</i>	1	Young Pil Kim et al., "Reliability Degradation of High Density DRAM Cell Transistor Junction Leakage Current Induced by Band-to-Defect tunneling Under the Off-State Bias-Temperature Stress," <u>IEEE</u> , 2001	
<i>me</i>	2	K. Saino et al., "Impact of Gate-Induced Drain Leakage Current on the Tail Distribution of DRAM Data Retention Time," <u>IEEE</u> , 2000	

Examiner Signature

Walter C. Lamber

Date Considered

7/15/06

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.